

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under  
Reexamination  
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Examiner

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Art Unit

3661

Page 1 of 1

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	B	US-2001/0001848	05-2001	OSHIZAWA et al.	701/210
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	D	US-			
	E	US-			
	F	US-			
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	I	US-			
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	K	US-			
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	M	US-			

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**NON-PATENT DOCUMENTS**

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